

Notice of References Cited	Application/Control No. 10/083,447	Applicant(s)/Patent Under Reexamination KISHIMOTO, KAZUNORI	
	Examiner John P Trimmings	Art Unit 2133	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-5,235,566	08-1993	Merrill, John F.	368/113
	C	US-			
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	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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	U	"Test Generation for Crosstalk Induced Delay to Integrated Circuits", Chen et al., 28-30 Sept 1999, IEEE Test Conference Proceedings, 1999, pp191-200.
	V	"Analysis of Cross-Talk Effects on Logic Delays in CMOS Integrated Circuits", Moll et al., 14-17 May 1991, Proceedings on 34th Midwest Symposium on Circuits and Systems, pp 387-390, Vol. 1.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.